

Notice of References Cited

Application/Control No.

09/706,274

Applicant(s)/Patent Under Reexam

Arney et al.

Examiner

Arlen Soderquist

Art Unit

1743

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V	Lowry, R. K. NSB Special Publication 1982, 400-72, 64-75.
W	Iannuzzi, M. Proceedings - Electronic Components Conference 1983, 33rd, 591-601.
X	Lin, A. W. et al, Proceedings - Electronic Components & Technology Conference 1991, 41st, 820-826.

^{*} A copy of this reference is not being furnished with this Office action. See-MPEP § 707.05(a).¹ Dates in MM-YYYY format are publication dates.² Classifications may be U.S. or foreign.

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W	Enlow, L. R. et al, SPIE1997, 3235, 314-321.
X	Foley, S. et al, IEEE International Reliability Physics Symposium Proceedings 1999, 37th, 213-220.

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